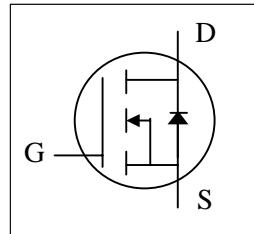
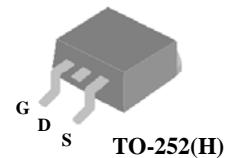




- ▼ 100%  $R_g$  & UIS Test
- ▼ Simple Drive Requirement
- ▼ Fast Switching Characteristic
- ▼ RoHS Compliant & Halogen-Free



$BV_{DSS}$	40V
$R_{DS(ON)}$	13.5mΩ
$I_D$	33A



## Description

AP4N013 series are from Advanced Power innovative design and silicon process technology to achieve the lowest possible on-resistance and fast switching performance. It provides the designer with an extreme efficient device for use in a wide range of power applications.

The TO-252 package is widely preferred for all commercial-industrial surface mount applications using infrared reflow technique and suited for high current application due to the low connection resistance.

## Absolute Maximum Ratings@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	40	V
$V_{GS}$	Gate-Source Voltage	+20	V
$I_D@T_c=25^\circ\text{C}$	Drain Current, $V_{GS} @ 10\text{V}$	33	A
$I_D@T_c=100^\circ\text{C}$	Drain Current, $V_{GS} @ 10\text{V}$	20.8	A
$I_{DM}$	Pulsed Drain Current <sup>1</sup>	120	A
$P_D@T_c=25^\circ\text{C}$	Total Power Dissipation	27.1	W
$P_D@T_A=25^\circ\text{C}$	Total Power Dissipation <sup>4</sup>	2	W
$E_{AS}$	Single Pulse Avalanche Energy <sup>3</sup>	16.2	mJ
$T_{STG}$	Storage Temperature Range	-55 to 150	°C
$T_J$	Operating Junction Temperature Range	-55 to 150	°C

## Thermal Data

Symbol	Parameter	Value	Units
$R_{thj-c}$	Maximum Thermal Resistance, Junction-case	4.6	°C/W
$R_{thj-a}$	Maximum Thermal Resistance, Junction-ambient (PCB mount) <sup>4</sup>	62.5	°C/W



# AP4N013H

## Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$ , $I_D=250\mu\text{A}$	40	-	-	V
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{\text{GS}}=10\text{V}$ , $I_D=18\text{A}$	-	-	13.5	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}$ , $I_D=12\text{A}$	-	-	22	$\text{m}\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$ , $I_D=250\mu\text{A}$	1	-	3	V
$g_f$	Forward Transconductance	$V_{\text{DS}}=5\text{V}$ , $I_D=18\text{A}$	-	42	-	S
$I_{\text{DSS}}$	Drain-Source Leakage Current	$V_{\text{DS}}=32\text{V}$ , $V_{\text{GS}}=0\text{V}$	-	-	10	$\text{uA}$
$I_{\text{GSS}}$	Gate-Source Leakage	$V_{\text{GS}}=\pm 20\text{V}$ , $V_{\text{DS}}=0\text{V}$	-	-	$\pm 100$	nA
$Q_g$	Total Gate Charge	$I_D=12\text{A}$	-	16	25.6	nC
$Q_{\text{gs}}$	Gate-Source Charge	$V_{\text{DS}}=32\text{V}$	-	4	-	nC
$Q_{\text{gd}}$	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=4.5\text{V}$	-	6	-	nC
$t_{\text{d}(\text{on})}$	Turn-on Delay Time	$V_{\text{DS}}=20\text{V}$	-	7	-	ns
$t_r$	Rise Time	$I_D=18\text{A}$	-	37	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time	$R_G=3.3\Omega$	-	24	-	ns
$t_f$	Fall Time	$V_{\text{GS}}=10\text{V}$	-	5	-	ns
$C_{\text{iss}}$	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	1630	2608	pF
$C_{\text{oss}}$	Output Capacitance	$V_{\text{DS}}=25\text{V}$	-	115	-	pF
$C_{\text{rss}}$	Reverse Transfer Capacitance	f=1.0MHz	-	90	-	pF
$R_g$	Gate Resistance	f=1.0MHz	-	1.1	2.5	$\Omega$

## Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$\text{V}_{\text{SD}}$	Forward On Voltage <sup>2</sup>	$I_S=18\text{A}$ , $V_{\text{GS}}=0\text{V}$	-	-	1.2	V
$t_{\text{rr}}$	Reverse Recovery Time	$I_S=18\text{A}$ , $V_{\text{GS}}=0\text{V}$ , $dI/dt=100\text{A}/\mu\text{s}$	-	9	-	ns
$Q_{\text{rr}}$	Reverse Recovery Charge		-	3	-	nC

## Notes:

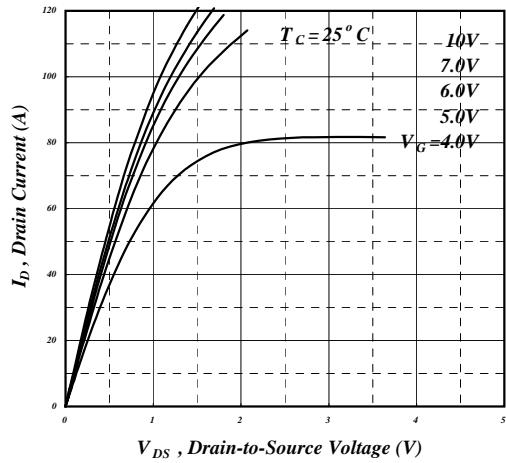
- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse test
- 3.Starting  $T_j=25^\circ\text{C}$  ,  $V_{\text{DD}}=40\text{V}$  ,  $L=0.1\text{mH}$  ,  $R_G=25\Omega$  ,  $V_{\text{GS}}=10\text{V}$
- 4.Surface mounted on 1 in<sup>2</sup> copper pad of FR4 board

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

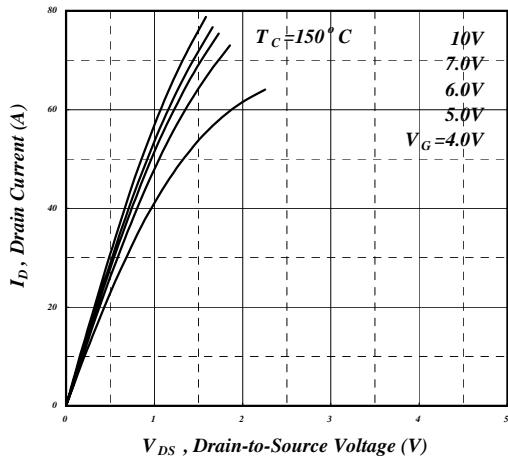
USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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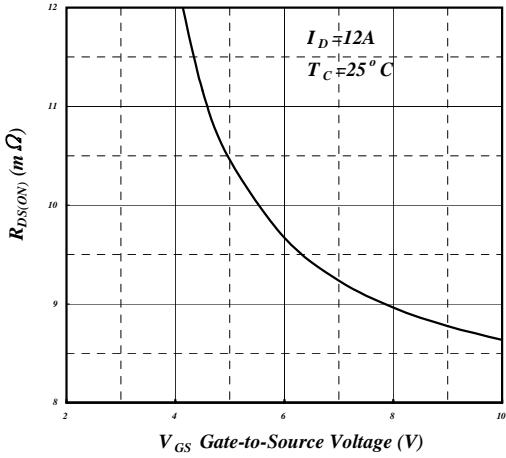
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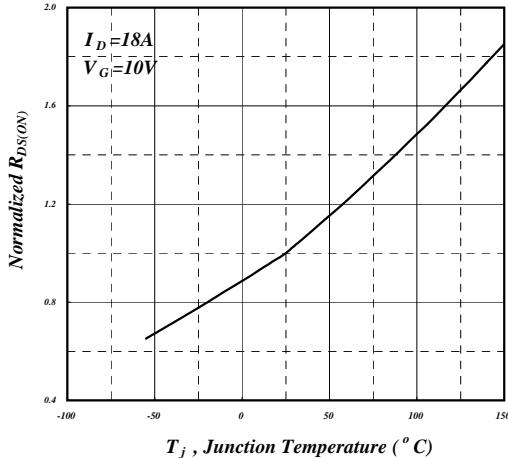
**Fig 1. Typical Output Characteristics**



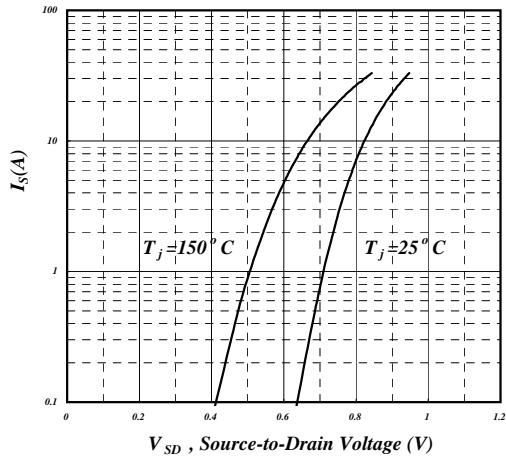
**Fig 2. Typical Output Characteristics**



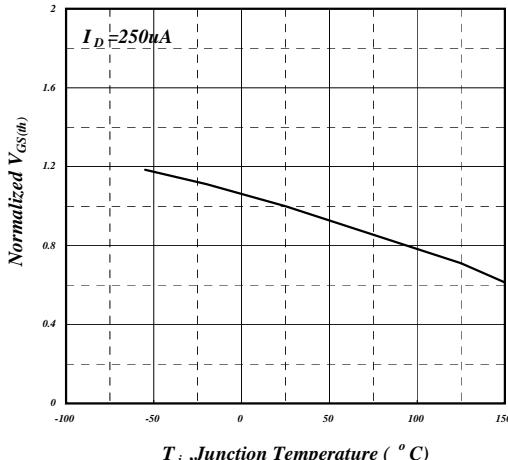
**Fig 3. On-Resistance v.s. Gate Voltage**



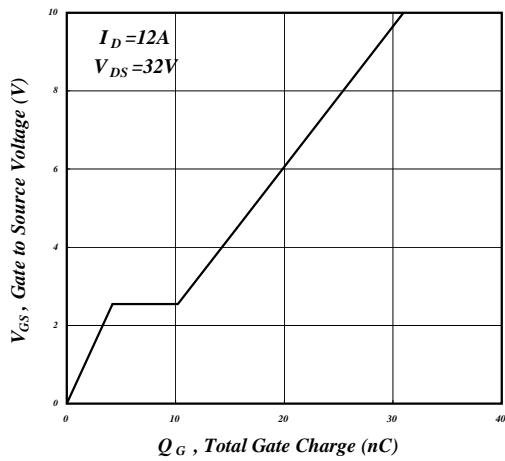
**Fig 4. Normalized On-Resistance v.s. Junction Temperature**



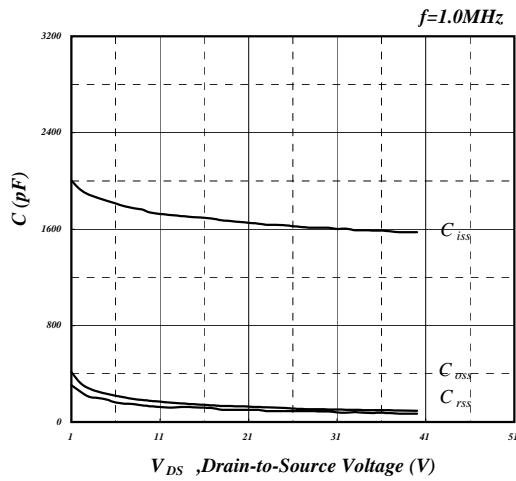
**Fig 5. Forward Characteristic of Reverse Diode**



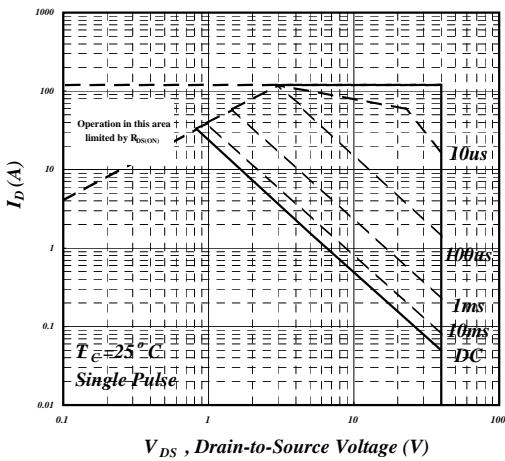
**Fig 6. Gate Threshold Voltage v.s. Junction Temperature**



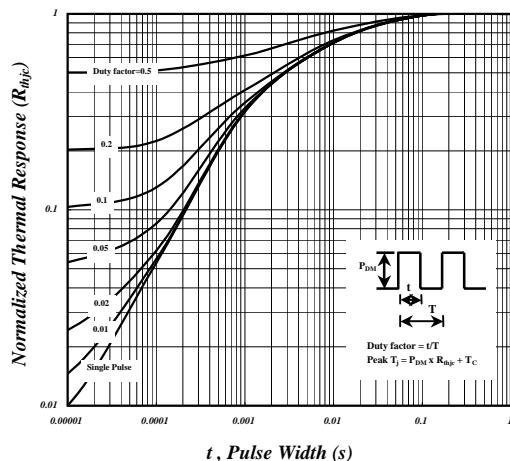
**Fig 7. Gate Charge Characteristics**



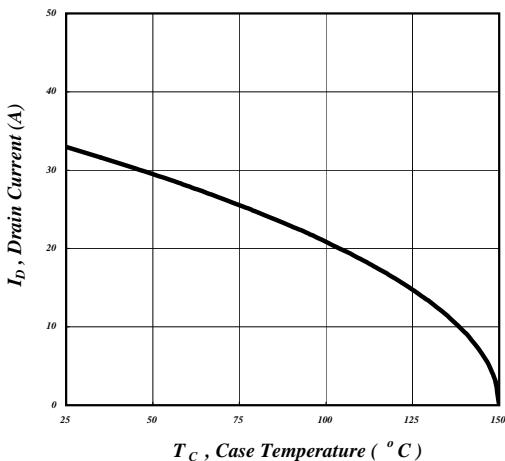
**Fig 8. Typical Capacitance Characteristics**



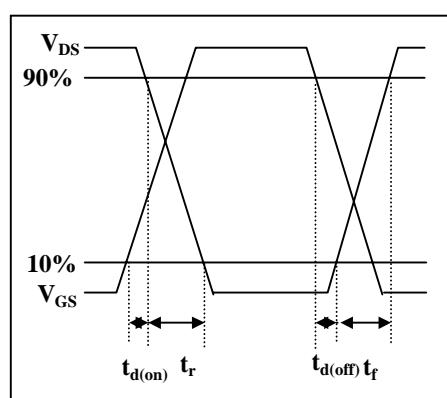
**Fig 9. Maximum Safe Operating Area**



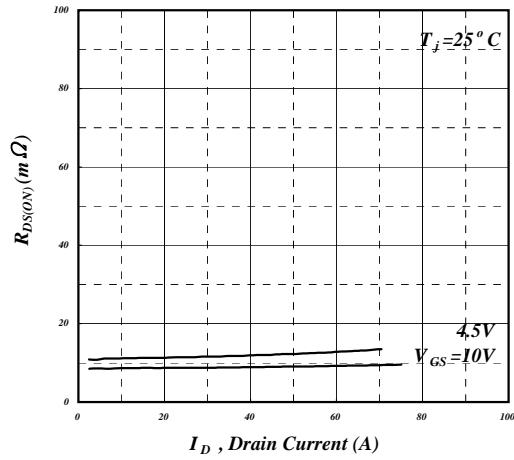
**Fig 10. Effective Transient Thermal Impedance**



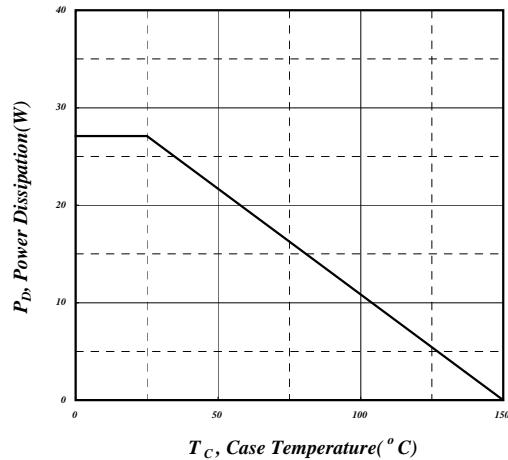
**Fig 11. Drain Current v.s. Case Temperature**



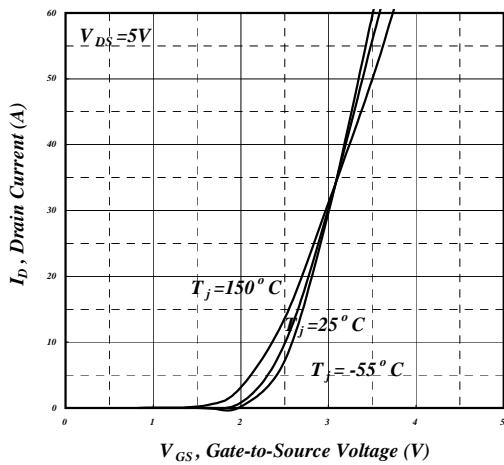
**Fig 12. Switching Time Waveform**



**Fig 13. Typ. Drain-Source on State Resistance**



**Fig 14. Total Power Dissipation**



**Fig 15. Transfer Characteristics**



**AP4N013H**

## **MARKING INFORMATION**

